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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/467,611	MIAO ET AL.	٠.
Examiner	Art Unit	
Jason M. Perilla	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	295	3/16/2007	JP
	316	3/16/2007	JP
	346	3/16/2007	JP
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
East USPAT/USPGPUB	3/16/2007	JP
Inventor Name Search EAST/EDAN	3/16/2007	JP
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